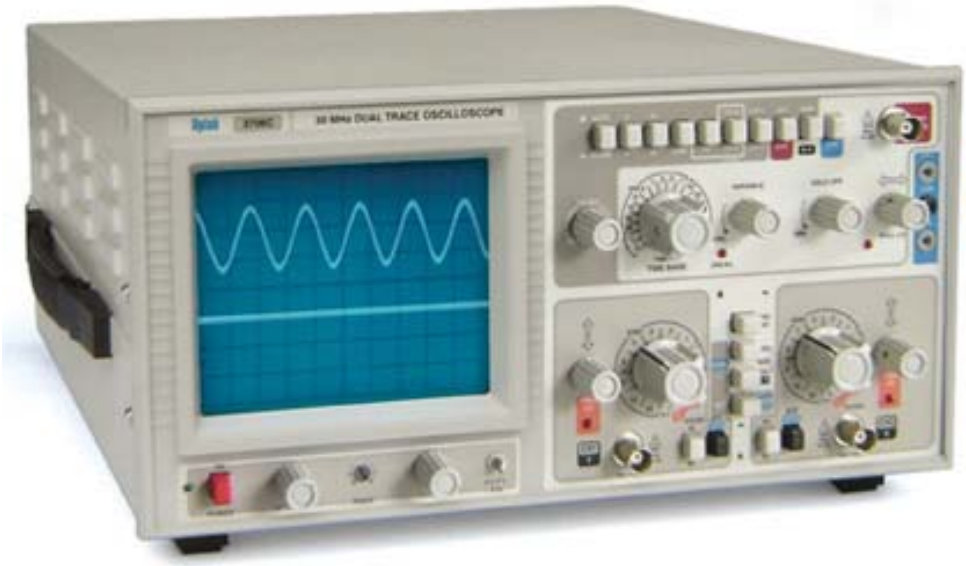
Aplab

30MHz DUAL TRACE OSCILLOSCOPE WITH COMPONENT TESTER 3706C



Features

- DC - 30MHz Bandwidth
- 1mV/div Sensitivity on Both Channels
- CH1, CH2 (Independent Channels), CH1 & CH2 (Alternate / CHOP), CH2 INVT, ADD and SUBTRACT
- X-Y Operation
- 40ns/div to 0.2s/div Time Base
- 140mm Rectangular CRT with Internal Graticule
- Triggering to 40MHz
- Z Modulation (TTL Level)
- 8 x 10 cm. Display
- TV Triggering Frame (V) & Line (H)
- MAINS Trigger
- Variable Hold Off
- Built-in Component Tester / Comparator

Technical Specifications

VERTICAL DEFLECTION

Deflection Coefficient (CH1 & CH2) : 1mV/div to 20V/div. 5mV/div to 20V/div in 12 calibrated steps in 1-2-5 sequence. x5 Magnification increases the sensitivity to 1mV/div & 2mV/div. (LED indicated).

Accuracy : ±3%.

Bandwidth : DC - 30MHz (-3dB), dc coupled. 10Hz -30MHz (-3dB), ac coupled. 20MHz (-3dB) in x5 MAG.

Rise-Time : 11.6 ns or less, 17.5ns in x5 MAG.

Display Modes : CH1, CH2, CH1 & CH2 Alternate or Chop mode, Algebraic addition CH1 + CH2, Algebraic subtraction CH1 - CH2, CH2 Invert & X-Y.

Input Impedance : 1 M ohms & 25 pF (approx).

Maximum Input Voltage : 400 Volts (dc + peak ac).

Internal Trigger Signal : CH1 or CH2 signal.

TIME BASE

Sweep Speed : 18 calibrated steps. 0.5 µs/div to 0.2 s/div in 1, 2 & 5 sequence.

Sweep Magnifier : x5 Magnification extends the sweep speed to 100 ns/div. x5 Magnification indication with LED.

Accuracy : ±3%.

Variable : Uncalibrated continuously variable control between steps, extends fastest sweep speed to 40 ns/div (approx). (Uncal LED indication).

Hold-off Time : 4:1 variable control.

TRIGGER SYSTEM

Triggering Mode : Automatic or Normal with Level Control.

Source : CH1 / CH2 / MAINS / EXT.

Slope : Positive or Negative.

Coupling : ac / dc / HF reject or TV Frame / TV Line.

Trigger Sensitivity :

Mode	*Freq - Range*	*INT*	*EXT*
AUTO	30Hz - 30MHz	1 div	1V p-p
NORM	3Hz - 30MHz	1 div	1V p-p

(Typical 40MHz at 2 div).

HORIZONTAL DEFLECTION

Deflection Coefficient : Same as CH2.

Bandwidth : DC - 1MHz (-3dB).

Input Impedance : 1M ohms and 25pF (approx).

COMPONENT TESTER / COMPARATOR

Dual Component Tester allows comparison of V-I characteristics of a Device - Under - Test (D.U.T.) and a sample Device.

Test Voltage : 8.6V r.m.s.

Test Current : 28mA.

Test Frequency : 50Hz or 60Hz.

GENERAL INFORMATION

Cathode Ray Tube : 140mm Rectangular screen, Internal Graticule, 8 x 10 cm, P31 phosphor. Accelerating potential : 2 kV.

Trace Rotation : Front Panel control, allows ±5^{O} of trace adjustment.

Z-Modulation : TTL level.

Calibrator : Provides 0.2V ±2%, 1KHz square-wave output for probe compensation.

Power Requirement : 230V AC ±10%, 47-65Hz, 40VA.

Dimensions : 165 (H) x 340 (W) x 420 (D) mm.

Weight : 7.5 Kgs. approx.

Standard Accessories : Instruction Manual, 2 Input BNC Leads.

Optional Accessories : High impedance switch probe with x1 or x10 attenuation (Model 306), Trolley.

Environmental Specifications : Normal : 10^{O}C to 40^{O}C RH 85%. Operational : 0^{O}C to 50^{O}C RH 85%.

WE PURSUE A POLICY OF CONTINUOUS DEVELOPMENT AND PRODUCT IMPROVEMENT. THUS THE SPECIFICATIONS IN THIS DOCUMENT AND THE LOCATION OF CONTROLS ON THE FRONT PANEL MAY BE CHANGED WITHOUT NOTICE.

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